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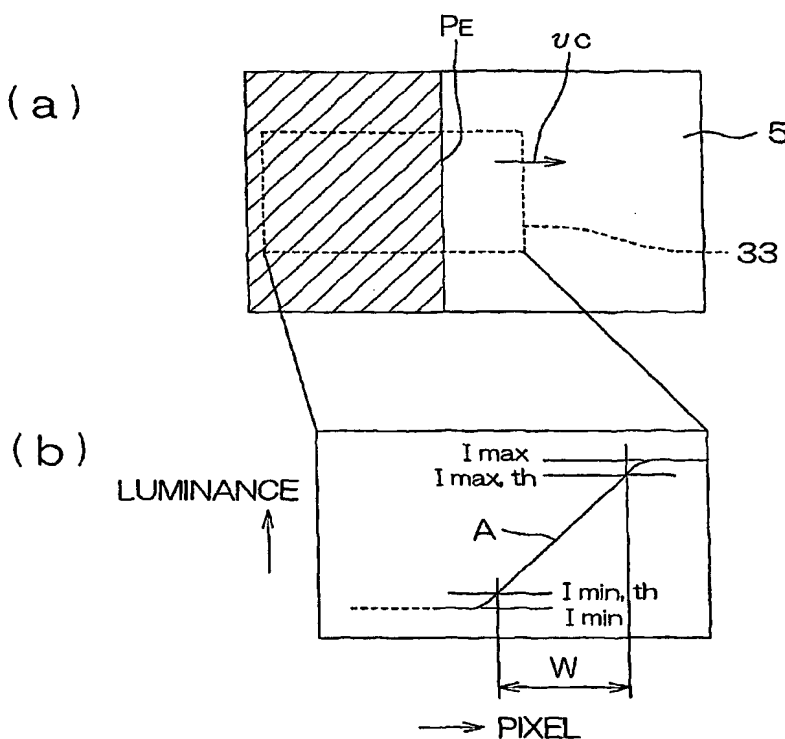
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(54) Title: METHOD AND SYSTEM FOR EVALUATING MOVING IMAGE QUALITY OF DISPLAYS



(57) Abstract: A test pattern is moved on a screen 5 subject to measurement with the field of view of an image sensor pursuing the motion of the test pattern so as to observe BEW. Subsequently, the field of view 33 of the image sensor is moved at the same velocity v_c as in the foregoing observation to capture an image of a static pattern PE, and a blur width W along the scrolling direction that appears in a distribution profile of the captured image is observed. Based upon the blur width W and the exposure time of the image sensor for capturing the image of the static pattern PE, the moving velocity of the test pattern at the time of observation of the BEW is estimated, and by using the moving velocity, the BEW is normalized. Evaluation of the moving image quality of the screen is carried out by using the normalized NBEW. The moving velocity of the original test pattern can thus be estimated easily and accurately, and accordingly, the moving image quality of the screen can be evaluated accurately.



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